

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/662,511 WATANABE ET AL.	
		Examiner	Art Unit Craig E. Church	2882 Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,369,678	11-1994	Chiu et al.	378/62
	B	US-5,040,199	08-1991	Stein, Jay A.	378/56
	C	US-6,845,142	01-2005	Ohishi, Satoru	378/8
	D	US-6,055,295	04-2000	Murthy et al.	378/151
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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